CD4048B Types

CMOS Multifunction Expandable 8-Input Gate

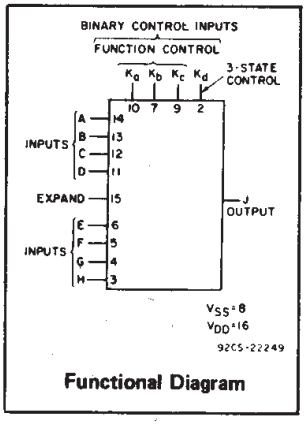
High-Voltage Types (20-Volt Rating)

■ CD4048B is an 8-input gate having four control inputs. Three binary control inputs — Ka, Kb, and Kc — provide the implementation of eight different logic functions. These functions are OR, NOR, AND, NAND, OR/AND, OR/NAND, AND/OR and AND/NOR.

A fourth control input, Kd, provides the user with a 3-state output. When control input Kd is high, the output is either a logic 1 or a logic 0 depending on the inner states. When control input Kd is low, the output is an open circuit. This feature enables the user to connect this device to a common bus line.

In addition to the eight input lines, an EXPAND input is provided that permits the user to increase the number of inputs into a CD4048B (see Fig. 2). For example, two CD4048B's can be cascaded to provide a 16-input multifunction gate. When the EXPAND input is not used, it should be connected to V_{SS}.

The CD4048B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).



Functional Diagram

MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD})	
Voltages referenced to V_{SS} Terminal)	-0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	-0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (P_D):	
For T_A = -55°C to +100°C	500mW
For T_A = +100°C to +125°C	Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)	100mW
OPERATING-TEMPERATURE RANGE (T_A)	-55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg})	-65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):	
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max	+265°C

Features:

- Three-state output
- Many logic functions available in one package
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V (full package-temperature range), 100 nA at 18 V and 25°C
- Noise margin (full package-temperature range) = 1 V at V_{DD}=5 V, 2 V at V_{DD} = 10 V, 2.5 V at V_{DD}=15 V
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Selection of up to 8 logic functions
- Digital control of logic
- General-purpose gating logic
  - Decoding
  - Encoding

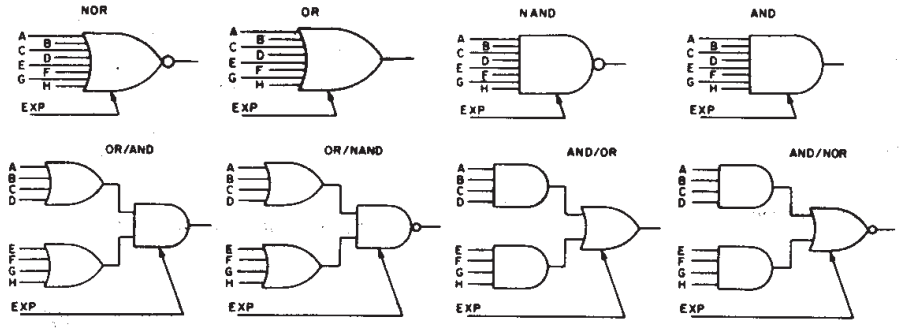
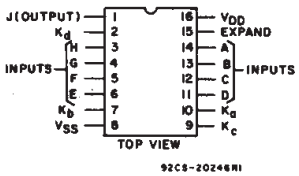


Fig. 1 — Basic logic configurations.



TERMINAL ASSIGNMENT

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range (For T_A = Full Package Temperature Range)	3	18	V

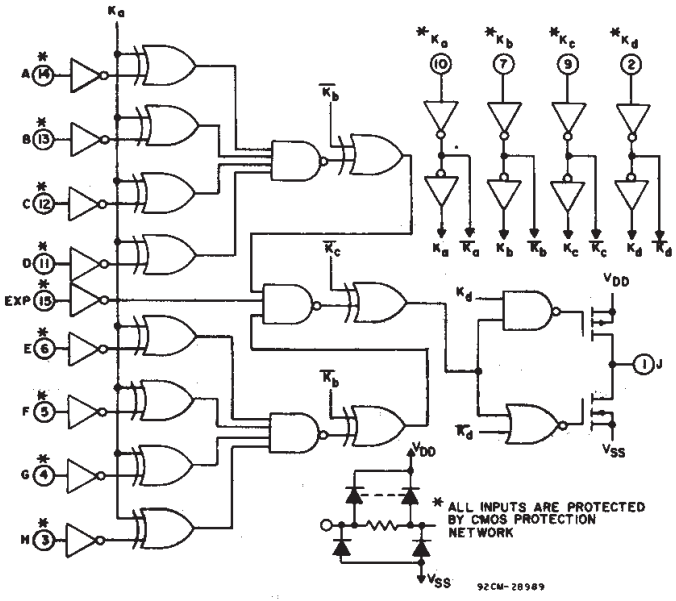


Fig. 2 – Logic diagram.

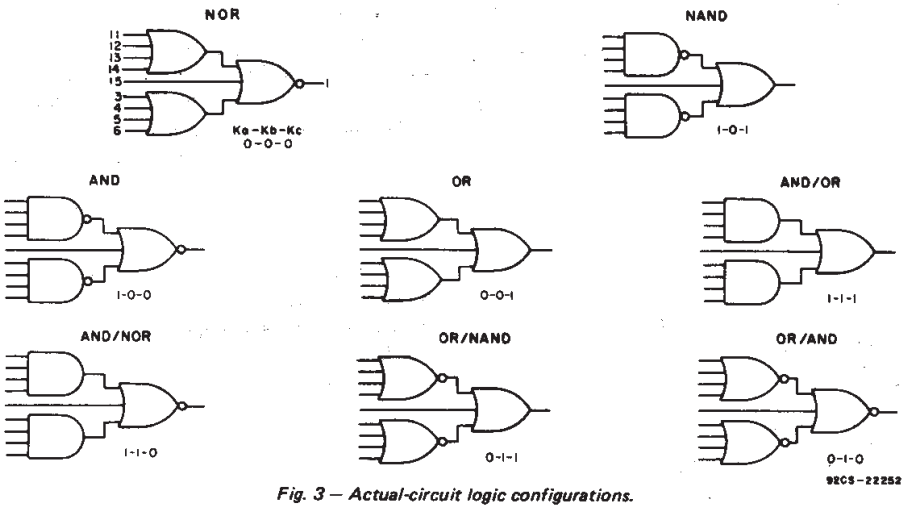
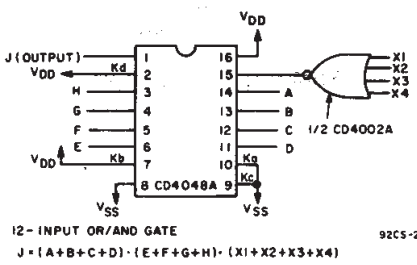


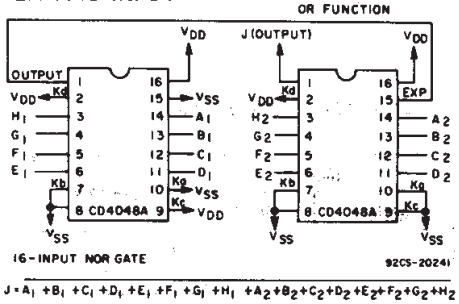
Fig. 3 – Actual-circuit logic configurations.

APPLICATIONS OF EXPAND INPUT



$J = (A+B+C+D)\cdot(E+F+G+H)\cdot(X1+X2+X3+X4)$

Fig. 4 – 12-input OR/AND gate.



$J = A_1+B_1+C_1+D_1+E_1+F_1+G_1+H_1+A_2+B_2+C_2+D_2+E_2+F_2+G_2+H_2$

Fig. 5 – 16-input NOR gate.

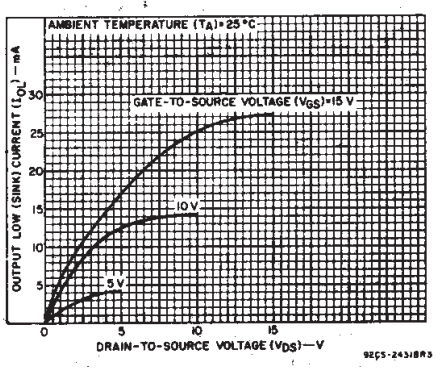


Fig. 6 – Typical output low (sink) current characteristics.

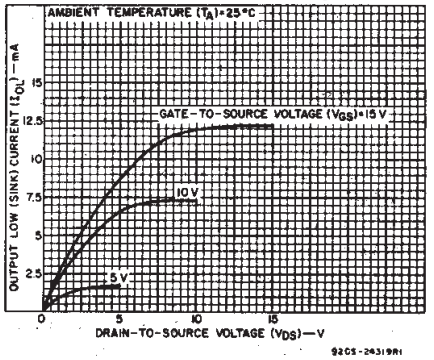


Fig. 7 – Minimum output low (sink) current characteristics.

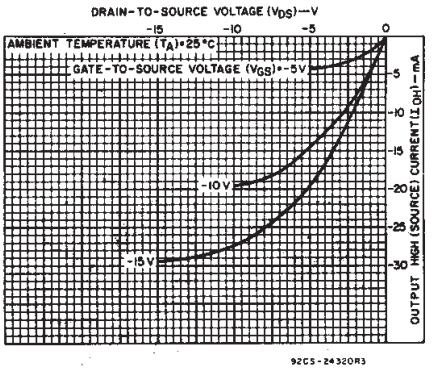


Fig. 8 – Typical output high (source) current characteristics.

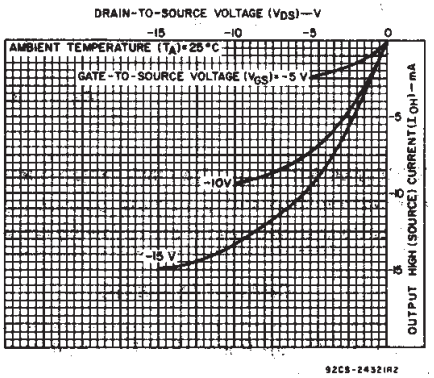


Fig. 9 – Minimum output high (source) current characteristics.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
								+25			
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	Min.	Typ.	Max.	
Quiescent Device Current, I_{DD} Max.	–	0,5	5	0.25	0.25	7.5	7.5	–	0.01	0.25	μA
	–	0,10	10	0.5	0.5	15	15	–	0.01	0.5	
	–	0,15	15	1	1	30	30	–	0.01	1	
	–	0,20	20	5	5	150	150	–	0.02	5	
Output Low (Sink) Current I_{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Output High (Source) Current, I_{OH} Min.	4.6	0,5	5	−0.64	−0.61	−0.42	−0.36	−0.51	−1	–	
	2.5	0,5	5	−2	−1.8	−1.3	−1.15	−1.6	−3.2	–	
	9.5	0,10	10	−1.6	−1.5	−1.1	−0.9	−1.3	−2.6	–	
	13.5	0,15	15	−4.2	−4	−2.8	−2.4	−3.4	−6.8	–	
Output Voltage: Low-Level, V_{OL} Max.	–	0,5	5	0.05				–	0	0.05	V
	–	0,10	10	0.05				–	0	0.05	
	–	0,15	15	0.05				–	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	–	0,5	5	4.95				4.95	5	–	
	–	0,10	10	9.95				9.95	10	–	
	–	0,15	15	14.95				14.95	15	–	
Input Low Voltage, V_{IL} Max.	0.5,4.5	–	5	1.5				—	—	1.5	V
	1,9	–	10	3				—	—	3	
	1.5,13.5	–	15	4				—	—	4	
Input High Voltage, V_{IH} Min.	0.5,4.5	–	5	3.5				3.5	—	—	
	1,9	–	10	7				7	—	—	
	1.5,13.5	–	15	11				11	—	—	
Input Current I_{IN} Max.		0,18	18	±0.1	±0.1	±1	±1	–	$±10^{-5}$	±0.1	μA
3-State Output Current, I_{OUT}	0,18	0,18	18	±0.4	±0.4	±12	±12	–	$±10^{-4}$	±0.4	μA

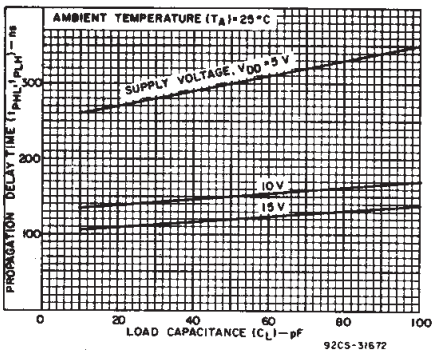


Fig. 10 – Typical propagation delay time (logic inputs to output) as a function of load capacitance.

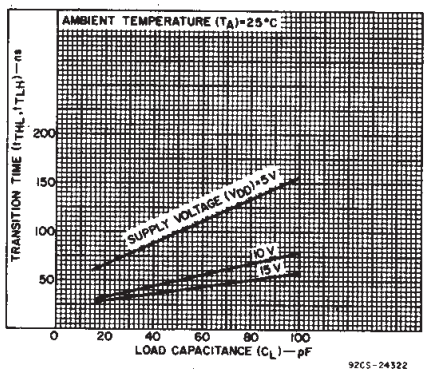


Fig. 11 – Typical transition time vs. load capacitance.

IMPLEMENTATION OF EXPAND INPUT FOR 9 OR MORE INPUTS

OUTPUT FUNCTION	FUNCTION NEEDED AT EXPAND INPUT	OUTPUT BOOLEAN EXPRESSION
NOR	OR	$J=\overline{(A+B+C+D+E+F+G+H)+(EXP)}$
OR	OR	$J=(A+B+C+D+E+F+G+H)+(EXP)$
AND	NAND	$J=(ABCDEFGH)\cdot\overline{(EXP)}$
NAND	NAND	$J=\overline{(ABCDEFGH)\cdot\overline{(EXP)}}$
OR/AND	NOR	$J=\overline{(A+B+C+D)\cdot(E+F+G+H)\cdot\overline{(EXP)}}$
OR/NAND	NOR	$J=(A+B+C+D)\cdot(E+F+G+H)\cdot\overline{(EXP)}$
AND/NOR	AND	$J=\overline{(ABCD)+(EFGH)+(EXP)}$
AND/OR	AND	$J=(ABCD)+(EFGH)+(EXP)$

Note: (EXP) designates the EXPAND function (i.e., $X_1+X_2+\ldots X_N$).

NOTE:
Refer to FUNCTION TRUTH TABLE for connection of unused inputs.

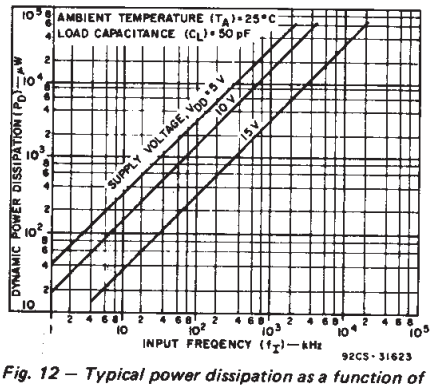


Fig. 12 – Typical power dissipation as a function of input frequency.

DYNAMIC CHARACTERISTICS at T_A=25°C, C_L=50 pF, Input t_r,t_f=20 ns, R_L=200 kΩ unless otherwise specified

CHARACTERISTIC	TEST CONDITIONS	V_{DD} V	LIMITS All Package Types Typ.	LIMITS All Package Types Max.	UNITS
Propagation Delay: t_{PHL},t_{PLH} Inputs to Output and Ka to Output		5	300	600	ns
		10	150	300	
		15	120	240	
Kb to Output		5	225	450	
		10	85	170	
		15	55	110	
Kc to Output		5	140	280	
		10	50	100	
		15	40	80	
Expand Input to Output		5	190	380	
		10	90	180	
		15	65	130	
3-State Propagation Delay: Kd to Output t_{PHZ},t_{PLZ} t_{PZH},t_{PZL}	R_L=1 kΩ See Fig.21	5	80	160	
		10	35	70	
		15	25	50	
Transition Time: t_{THL},t_{TLH}		5	100	200	
		10	50	100	
		15	40	80	
Input Capacitance: C_I	Any Input		5	7	pF
3-State Output Capacitance			5	10	

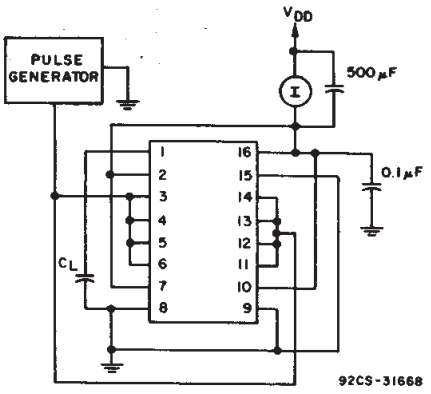


Fig. 13 – Dynamic power dissipation test circuit.

FUNCTION TRUTH TABLE

OUTPUT FUNCTION	BOOLEAN EXPRESSION	K_a	K_b	K_c	UNUSED INPUT*
NOR	$J=\overline{A+B+C+D+E+F+G+H}$	0	0	0	V_{SS}
OR	$J=A+B+C+D+E+F+G+H$	0	0	1	V_{SS}
OR/AND	$J=(A+B+C+D)\cdot(E+F+G+H)$	0	1	0	V_{SS}
OR/NAND	$J=\overline{(A+B+C+D)\cdot(E+F+G+H)}$	0	1	1	V_{SS}
AND	$J=ABCDEFGH$	1	0	0	V_{DD}
NAND	$J=\overline{ABCDEFGH}$	1	0	1	V_{DD}
AND/NOR	$J=\overline{ABCD+EFGH}$	1	1	0	V_{DD}
AND/OR	$J=ABCD+EFGH$	1	1	1	V_{DD}

K_d=1 Normal Inverter Action

K_d=0 High Impedance Output

EXPAND Input=0

* See Figs. 1,2,3,4, and 5.

TEST CIRCUITS - STATIC MEASUREMENTS

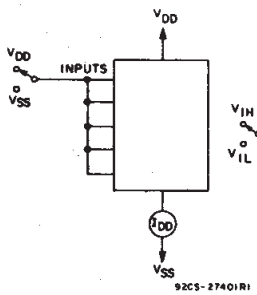


Fig. 14 – Quiescent device current test circuit.

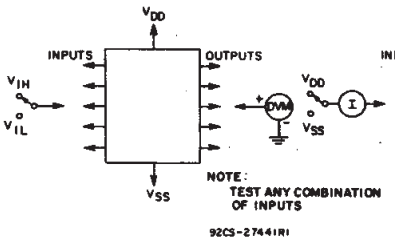


Fig. 15 – Input voltage test circuit.

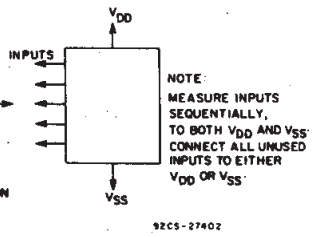


Fig. 16 – Input current test circuit.

TEST CIRCUITS - DYNAMIC MEASUREMENTS

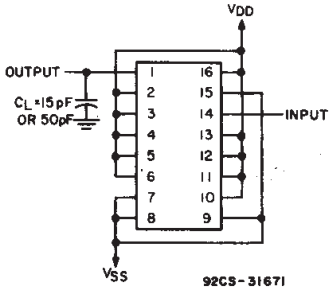


Fig. 17 – Test circuit for t_{PHL}, t_{THL}, and t_{TLH} (AND) measurements.

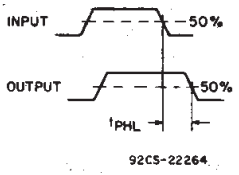


Fig. 18 – Waveforms for t_{PHL} and t_{PHL} (AND).

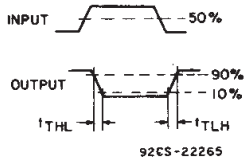


Fig. 19 – Waveforms for t_{THL} and t_{TLH} (AND).

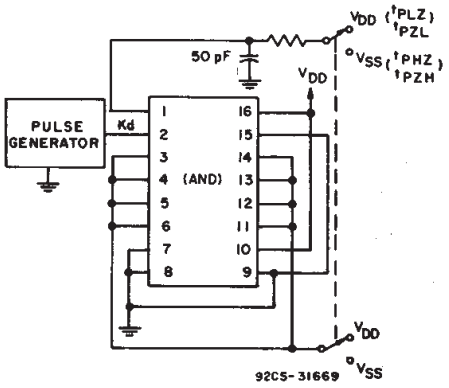


Fig. 20 – Test circuit for t_{PZL}, t_{PZH}, t_{PLZ}, and t_{PHZ} (AND).

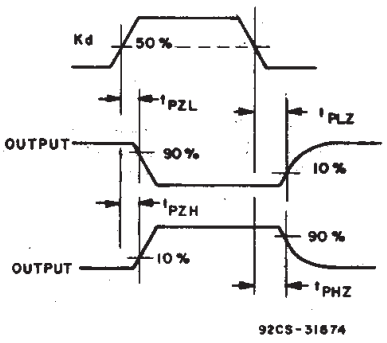
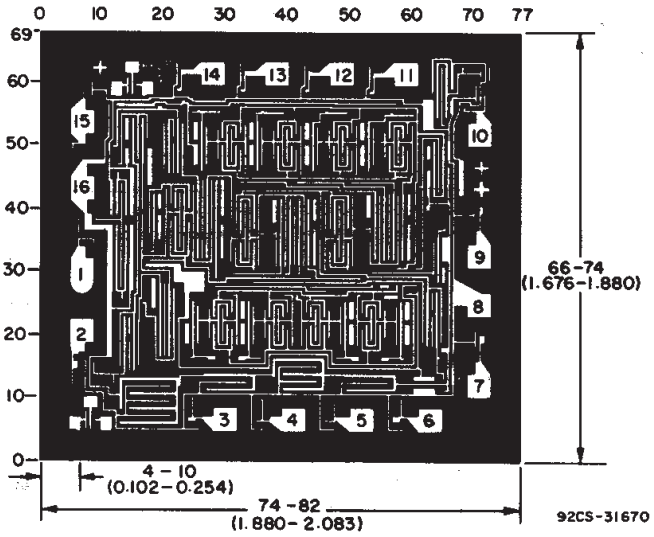


Fig. 21 – Waveforms for t_{PZL}, t_{PZH}, t_{PLZ}, and t_{PHZ} (AND).



Dimensions and pad layout for CD4048BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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